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| INFORMATION DISCLOSURE STATEMENT PTO-1449 | Applicant(s): MARUTA, Yukio, et al. | Serial No. 10/708,587 |
| | Filing Date: March 12, 2004 | Group Art Unit: Unassigned |
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U.S. PATENT DOCUMENTS

| Examiner Initial | Document No. | Name | Date | Class | Subclass | Filing Date (If appropriate) |
|---------------------|--------------|------|------|-------|----------|------------------------------------|
| _____ | AA | | | | | |
| _____ | AB | | | | | |
| _____ | AC | | | | | |
| _____ | AD | | | | | |

FOREIGN PATENT DOCUMENTS

| Document No. | Date | Country | Translation (Yes or No) |
|--------------|------|---------|----------------------------|
| _____ | AE | | |
| _____ | AF | | |
| _____ | AG | | |
| _____ | AH | | |
| _____ | AI | | |

OTHER DOCUMENTS

| | | |
|--|----|---|
| <u>7P</u> | AJ | "Achieving Quick Design Debugging With Circuit Correction Function Using Focused Ion Beam Technique"; IBM, June 23, 1999, http://www-6.ibm.com/jp/chips/v5_1/mn51011.html . |
| _____ | AK | |
| Examiner <u>RPICVRENT</u> Date Considered <u>6/22/05</u> | | |